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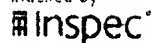  Maximum 100
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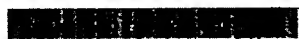
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☐     1. **The Noaa Geosat Program: Monitoring Tropical Sea Level With Satellite /**
Cheney, R.; Douglas, B.; Miller, L.; Agreen, R.; Doyle, N.;
Geoscience and Remote Sensing Symposium, 1989. IGARSS'89. 12th Canadi
on Remote Sensing. 1989 International
Volume 2, July 10 -14th 1989 Page(s):1053 - 1053

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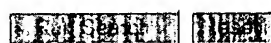
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measurement <or> etch <or> etching)
<phrase> ((group <or> set <or> assortment
<or> plurality <or> number <or> many <or>
several) <phrase> (sample <or> wafer <or>
die <or> dice)))
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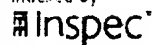IEEE CNF   IEEE Conference Proceeding

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               ⌐    **1. Experimental characterization of resistive joints for use inside ATLAS tor**
                       Volpini, G.; Baccaglioni, G.; Pojer, M.;
                       Applied Superconductivity, IEEE Transactions on
                       Volume 11, Issue 1, Part 2, March 2001 Page(s):2130 - 2133
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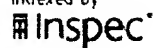| IEEE JNL | IEEE Journal or Magazine |
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plural <or> numerous)<phrase> (wafers
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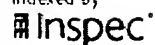
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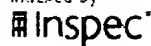IEEE CNF    IEEE Conference          **No results were found.**
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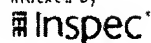**» Organize results**
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☐   1. **Application of combined optimum control and estimation theory to direct**
Wells, C.H.; Larson, R.E.;
Proceedings of the IEEE
Volume 58, Issue 1, Jan. 1970 Page(s):16 - 22
AbstractPlus | Full Text: PDF(596 KB)   IEEE JNL

☐   2. **Sufficient conditions for hyperstability of a class of nonlinear systems**
Chang Han;
Automatic Control, IEEE Transactions on
Volume 15, Issue 6, Dec 1970 Page(s):705 - 706
AbstractPlus | Full Text: PDF(304 KB)   IEEE JNL

☐   3. **Stabilized suboptimal periodic control of a chemical reactor**
Matsubara, M.; Onogi, K.;
Automatic Control, IEEE Transactions on
Volume 23, Issue 6, Dec 1978 Page(s):1005 - 1008
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☐   4. **Filtering in nonlinear time delay systems**
Yu, T.; Seinfeld, J.; Ray, W.;
Automatic Control, IEEE Transactions on
Volume 19, Issue 4, Aug 1974 Page(s):324 - 333
AbstractPlus | Full Text: PDF(840 KB)   IEEE JNL

☐   5. **Modern Wiener-Hopf design of optimal controllers--Part II: The multivaria**
Youla, D.; Jabr, H.; Bongiorno, J., Jr.;
Automatic Control, IEEE Transactions on
Volume 21, Issue 3, Jun 1976 Page(s):319 - 338
AbstractPlus | Full Text: PDF(1544 KB)   IEEE JNL

☐   6. **Unstable suboptimal periodic control of a certain chemical reactor**
Matsubara, M.; Onogi, K.;
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Volume 23, Issue 6, Dec 1978 Page(s):1111 - 1113
AbstractPlus | Full Text: PDF(312 KB)   IEEE JNL

⌐  **7. Application of higher order bifurcation formulas**
Colantoni, M.C.; Padin, M.; Desages, A.; Romagnoli, J.A.;
Automatic Control, IEEE Transactions on
Volume 36, Issue 6, June 1991 Page(s):746 - 749
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⌐  **8. Computing bifurcation points via characteristics gain loci**
Moiola, J.; Desages, A.; Romagnoli, J.;
Automatic Control, IEEE Transactions on
Volume 36, Issue 3, March 1991 Page(s):358 - 362
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⌐  **9. The successive approximation procedure for finite-time optimal control o systems**
Aganovic, Z.; Gajic, Z.;
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Volume 39, Issue 9, Sept. 1994 Page(s):1932 - 1935
Digital Object Identifier 10.1109/9.317128

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⌐  **10. SVD-NET: an algorithm that automatically selects network structure**
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⌐  **11. Dynamic process monitoring and fault diagnosis with qualitative models**
Vinson, J.M.; Ungar, L.H.;
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Volume 25, Issue 1, Jan. 1995 Page(s):181 - 189
Digital Object Identifier 10.1109/21.362954

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⌐  **12. Robust feedback stabilization of chemical reactors**
Viel, F.; Jadot, F.; Bastin, G.;
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Digital Object Identifier 10.1109/9.566657

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⌐  **13. An algebraic criterion for robust stability of linear control systems**
Dainson, B.E.; Lewin, D.R.;
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Volume 43, Issue 2, Feb. 1998 Page(s):237 - 241
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⌐  **14. Predictive control of a bench-scale chemical reactor based on neural-net**
Schenker, B.; Agarwal, M.;
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   ⌐   **resistance measurement apparatus**
Firebaugh, S.L.; Jensen, K.F.; Schmidt, M.A.;
Microelectromechanical Systems, Journal of
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   ⌐   16. **Plasma-assisted chemical process for NO$_x$ control**
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Industry Applications, IEEE Transactions on
Volume 36, Issue 3, May-June 2000 Page(s):923 - 927
Digital Object Identifier 10.1109/28.845073

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   ⌐   17. **Miniaturization and integration of photoacoustic detection with a microfa**
**chemical reactor system**
Firebaugh, S.L.; Jensen, K.F.; Schmidt, M.A.;
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Volume 10, Issue 2, June 2001 Page(s):232 - 237
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   ⌐   18. **Fabrication of air-channel structures for microfluidic, microelectromecha**
**microelectronic applications**
Bhusari, D.; Reed, H.A.; Wedlake, M.; Padovani, A.M.; Allen, S.A.B.; Kohl, P.A
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Volume 10, Issue 3, Sept. 2001 Page(s):400 - 408
Digital Object Identifier 10.1109/84.946793

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   ⌐   19. **Towards ideal NO$_x$ control technology using a plasma-chemical hybrid p**
Yamamoto, T.; Okubo, M.; Hayakawa, K.; Kitaura, K.;
Industry Applications, IEEE Transactions on
Volume 37, Issue 5, Sept.-Oct. 2001 Page(s):1492 - 1498
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   ⌐   20. **Application of iterative learning control to an exothermic semibatch chen**
Mezghani, M.; Roux, G.; Cabassud, M.; Le Lann, M.V.; Dahhou, B.; Casamatt:
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Volume 10, Issue 6, Nov. 2002 Page(s):822 - 834
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AbstractPlus | References | Full Text: PDF(582 KB)   IEEE JNL

   ⌐   21. **Simultaneous removal of NO/sub x/, SO/sub x/, and CO/sub 2/ at elevatec**
**using a plasma-chemical hybrid process**
Yamamoto, T.; Okubo, M.; Nagaoka, T.; Hayakawa, K.;
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Volume 38, Issue 5, Sept.-Oct. 2002 Page(s):1168 - 1173
Digital Object Identifier 10.1109/TIA.2002.802911

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Control Systems Magazine, IEEE
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Digital Object Identifier 10.1109/MCS.2002.1035217

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Arana, L.R.; Schaevitz, S.B.; Franz, A.J.; Schmidt, M.A.; Jensen, K.F.;
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Aguilar-Lopez, R.; Alvarez-Ramirez, J.;
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Volume 149, Issue 4, July 2002 Page(s):263 - 268
Digital Object Identifier 10.1049/ip-cta:20020558

AbstractPlus | Full Text: PDF(450 KB)    IEE JNL

25. **Robust linearising controllers for nonlinear time-delay systems**
Wu, W.;
Control Theory and Applications, IEE Proceedings-
Volume 146, Issue 1, Jan. 1999 Page(s):91 - 97
Digital Object Identifier 10.1049/ip-cta:19990377

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<and> (expose <or> exposing <or> exposed)
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<or> portion)
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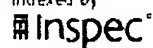IEEE CNF   IEEE Conference            **No results were found.**
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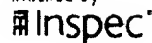» **Organize results**

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Polla, D.L.; Muller, R.S.; White, R.M.;
Electron Device Letters, IEEE
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Battey, J.F.;
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Sheppard, N.F.; Appelman, H.R.; Poh, S.Y.; Senturia, S.D.;
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Ephrath, L.M.;
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Hirai, Y.; Sasago, M.; Masayuki Endo; Tsuji, K.; Mano, Y.;
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   Campbell, W.; Thomas, U., Jr.;
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   Shah, J.; Hahn, W.;
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    Stewart, I.;
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11. **Gamma-ray radiation effects on hydroxyl absorption increase in optical f**
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    Uesugi, N.; Kuwabara, T.; Ishida, Y.; Noguchi, K.; Negishi, Y.; Uchida, N.;
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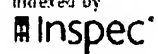
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Licci, F.; Asti, G.;
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Schaefer, G.;

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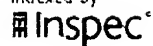
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